Unpublished Book Chapter by Charles Majkrtak

be increased accordingly.

## 6. Instrumental Configurations and Efficiencies

In this section we will describe the corrections which must be made for imperfect polarizer and flipper efficiencies in extracting spin-dependent cross sections from measured intensities. For the purpose of illustration, we will consider a conventional triple-axis spectrometer configuration with polarized beam incident on the sample and with one-dimensional polarization analysis of the scattered beam where only the final neutron spin eigenstate is determined. The same fundamental principles apply to time-of-flight instruments.

A schematic of a triple-axis spectrometer is shown in Figure 6-1 with monochromator, analyser, polarizers, and flippers such that, in the most general case, spin-dependent elastic or inelastic scattering cross sections can be obtained. We will make the explicit stipulation that any beam depolarization which occurs within the guide field be included as part of the effective polarization efficiency of the appropriate polarizing element, depending upon where the depolarization occurs, i.e., prior to or following the sample. We also take the flippers to be perfectly transparent and attribute any transmission losses (in the wire windings of a flat coil flipper, for example) to be incorporated in the effective reflection efficiencies of the monochromator-polarizer or analyzer-polarizer devices. We can then represent our spectrometer by the somewhat simpler schematic shown in Figure 6-2.

Our goal, again, is to obtain four spin-dependent cross sections, namely  $\sigma_{++}$ ,  $\sigma_{-}$ ,  $\sigma_{+}$  and  $\sigma_{-+}$ , from four measured intensities, I off off, I  $\infty$  off, I off off, and I off off where the superscripts off and on signify whether the front or rear flipper is off (no spin flip) or on ( $\tau$  spin turn), respectively. If only a single superscript appears, it refers specifically to the front flipper and the status of the rear flipper is automatically assumed to be either off or irrelevant.

The first question we need to ask is what are the intensities of + and - neutrons incident on the sample with the front flipper either off or on. Identifying the intensities incident on the sample by the subscript "o", we can write

$$I_{\text{off}} = I_{\text{off}} + I_{\text{off}}$$

and

X

$$I_0^{\alpha \alpha} = I_{\alpha +}^{\alpha \alpha} + I_0^{\alpha \alpha} \tag{6-1}$$

where

and where the subscripts "+" and "-" signify the + and - neutron spin eigenstates. Of course, if the efficiencies of the front polarizer and flipper were perfect and no instrumental depolarization occurred, then

$$I_{\circ}^{\text{ off }} = I_{\circ +}^{\text{ off }} \text{ (or } I_{\circ -}^{\text{ off)}} \text{ and } I_{\circ}^{\text{ oa}} = I_{\circ -}^{\text{ oa}} \text{ (or } I_{\circ +}^{\text{ oa}}).$$

If we define the quantity  $\phi$  to represent a fraction of the beam intensity, then we can write

$$\frac{I_{o+}^{eff}}{I_o} + \frac{I_{o-}^{eff}}{I_o} = \phi_{o+}^{eff} + \phi_{o-}^{eff} = 1$$
 (6-2)

so that the polarization of the beam incident on the sample with the front flipper off, Poff, is given by

$$P_o^{\text{off}} = \phi_{o+}^{\text{off}} - \phi_o^{\text{off}}$$
 (6-3)

Analogously, when the front flipper is on,

$$\frac{I_{o+}^{on}}{I_{o}} + \frac{I_{o-}^{on}}{I_{o}} \equiv \phi_{o+}^{on} + \phi_{o-}^{on} = 1$$
 (6-4)

so that

and

$$P_o^{\alpha} = \phi_{o+}^{\alpha} - \phi_o^{\alpha} \tag{6-5}$$

Now the  $\phi$ 's defined in equations (6-2) and (6-4) are related through the flipping efficiency of the front flipper which we shall define as f (0  $\leq$  f  $\leq$  1):

$$\phi_{o+}^{oa} = f \phi_{o}^{off} + (1 - f) \phi_{o+}^{off}$$
(6-6)

$$\phi_{c}^{oa} = f \phi_{oa}^{off} + (1 - f) \phi_{o}^{off}$$

so that

$$P_o^{\text{os}} = P_o^{\text{off}} (1-2f) \tag{6-7}$$

If we now take  $P_o^{off}$  to be the efficiency of the front polarizer and call it F, then the intensities incident on the sample are given by

$$I_{o+}^{off} = \frac{I_o}{2}(1+F)$$

$$I_{o-}^{off} = \frac{I_o}{2}(1-F)$$

$$I_{o+}^{on} = \frac{I_o}{2}[1+F(1-2f)]$$

$$I_{o-}^{on} = \frac{I_o}{2}[1-F(1-2f)]$$
(6-8)

Next, the intensities scattered by the sample, I, are, in general, given by

$$I_{s+}^{\text{off}} = \sigma_{++} I_{0+}^{\text{off}} + \sigma_{-+} I_{0-}^{\text{off}}$$

$$I_{s-}^{\text{off}} = \sigma_{-} I_{0-}^{\text{off}} + \sigma_{+-} I_{0+}^{\text{off}}$$

$$I_{s+}^{\text{oa}} = \sigma_{++} I_{0+}^{\text{oa}} + \sigma_{-+} I_{0-}^{\text{oa}}$$

$$I_{s-}^{\text{oa}} = \sigma_{-} I_{0-}^{\text{oa}} + \sigma_{+-} I_{0+}^{\text{oa}}$$

$$\times$$
(6-9)

where  $0 \le \sigma$ 's  $\le 1$ .

Finally, we need to determine the intensities  $I_D$  measured in the detector with the rear flipper either off or on. Consider first the case with the rear flipper off. Let the rear polarizer have a polarizing efficiency R ( $0 \le R \le 1$ ). The reflectivity of the rear polarizer is then

proportional to (1 + R) for + neutrons and to (1 - R) for - neutrons. Consequently, the intensities  $I_D$  which can be measured in the detector with the rear flipper off are

$$I_{D}^{\text{ off off}} = C [I_{s+}^{\text{ off}} (1 + R) + I_{s-}^{\text{ off}} (1 - R)]$$

and

$$I_{\rm B}^{\,\rm oa\,\,off} = C \left[ I_{*+}^{\,\rm oa} \left( 1 + {\rm R} \right) + I_{*-}^{\,\rm oa} \left( 1 - {\rm R} \right) \right]$$
 (6-10)

where C is a normalization constant to be derived below.

Now if the rear flipper is on and we designate its efficiency to be r ( $0 \le r \le 1$ ), then the intensities scattered by the sample after traversing the rear flipper are

$$I_{s+}^{\text{off on}} = r I_{s+}^{\text{off}} + (1-r) I_{s+}^{\text{off}}$$

$$I_{s-}^{\text{off on}} = r I_{s+}^{\text{off}} + (1-r) I_{s-}^{\text{off}}$$

$$I_{s+}^{\text{on on}} = r I_{s+}^{\text{on}} + (1-r) I_{s-}^{\text{on}}$$

$$I_{s+}^{\text{on on}} = r I_{s+}^{\text{on}} + (1-r) I_{s-}^{\text{on}}$$
(6-11)

The remaining intensities  $I_D$  which can be measured in the detector with the rear flipper on are then

$$I_{D}^{\text{off on}} = C \left[ I_{s+}^{\text{off on}} (1+R) + I_{s-}^{\text{off on}} (1-R) \right]$$

$$I_{D}^{\text{on on}} = C \left[ I_{s+}^{\text{on on}} (1+R) + I_{s-}^{\text{on on}} (1-R) \right]$$
(6-12)

If we now go back and substitute into equations (6-9) the expressions for the  $I_o$ 's given by equations (6-8), then equations (6-10), (6-11), and (6-12) can in turn be simplified and written in terms of  $I_o$ , F, R, f, r and C. The  $I_D$ 's are then given by (defining  $I_o$   $C/2 \equiv \beta$ )

$$I_{D}^{\text{off off}}/\beta = \sigma_{++} (1+F) (1+R) + \sigma_{-+} (1-F) (1+R) + \sigma_{-} (1-F) (1-R) + \sigma_{+-} (1+F) (1-R)$$
(6-13)

$$I_{D}^{\text{occ off}}/\beta = \sigma_{++} (1+R) [1 + F(1-2f)] + \sigma_{-+} (1+R) [1 - F(1-2f)] + \sigma_{-} (1-R) [1 - F(1-2f)] + \sigma_{+-} (1-R) [1 + F(1-2f)]$$
(6-14)

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$$I_{D}^{\text{off os}}/\beta = \sigma_{++} (1+F) [1 + R(1-2r)] + \sigma_{-+} (1-F) [1 + R(1-2r)] + \sigma_{-} (1-F) [1 - R(1-2r)] + \sigma_{+-} (1+F) [1 - R(1-2r)]$$
(6-15)

and

$$I_{D}^{\infty \infty}/\beta = \sigma_{++} [1 + F (1-2f)] [1 + R (1-2r)] + \sigma_{-+} [1 - F (1-2f)] [1 + R (1-2r)] + \sigma_{-} [1 - F (1-2f)] [1 - R (1-2r)] + \sigma_{+} [1 + F (1-2f)] [1 - R (1-2r)]$$
(6-16)

Equations (6-13, 14, 15, 16) are of general utility. Given the instrumental polarizing and flipping efficiencies F, R, f, and r, and the normalization parameter  $\beta$ , this set of equations can be solved for  $\sigma_{++}$ ,  $\sigma_{-}$ ,  $\sigma_{+-}$ , and  $\sigma_{-+}$  in terms of the measured intensities  $I_D^{\text{off off}}$ ,  $I_D^{\text{ond onf}}$ , and  $I_D^{\text{ond off}}$ .

We need, however, to address the problem of determining the instrumental parameters F, R, f, r, and  $\beta$ . Suppose that intensities  $I_{NS}$  are measured with no sample ("NS") in the beam.

Then  $\sigma_{++} = \sigma_{-} = 1$  and  $\sigma_{+-} = \sigma_{-+} = 0$  and equations (6-13, 14, 15, 16) reduce to

$$I_{NS}^{\text{off off}} = 2\beta [1 + FR]$$

$$I_{NS}^{\text{on off}} = 2\beta [1 + (1-2f) FR]$$

$$I_{NS}^{\text{off on}} = 2\beta [1 + (1-2r) FR]$$

$$I_{NS}^{\text{on on}} = 2\beta [1 + (1-2f) (1-2r) FR]$$
(6-17)

From the above equations (6-17) we obtain

Formula for 
$$2\beta = \frac{I_{NS}^{\text{onon}} \quad I_{NS}^{\text{offoff}} - I_{NS}^{\text{onoff}} \quad I_{NS}^{\text{offon}}}{I_{NS}^{\text{onon}} + I_{NS}^{\text{offoff}} - I_{NS}^{\text{onoff}} - I_{NS}^{\text{offon}}}$$
(6-18)

For mular 
$$(6-19)$$
 for  $pf \times pr$   $(6-19)$  for  $pf \times pr$   $(6-20)$  for  $pf \times pr$   $(6-20)$  for  $pf \times pr$   $(6-20)$ 

Thus all the parameters except the separate values of F and R are determined by measuring intensities without a sample. In order to obtain F and R individually, we need to make one more set of measurements, this time with a sample for which  $\sigma_{+-} = \sigma_{-+} = 0$  but  $\sigma_{++}$  and  $\sigma_{-}$  are different, the bigger the difference, the better. In fact, the actual values of  $\sigma_{++}$  and  $\sigma_{-}$  need not be known at all (except that they are sufficiently different!). If we measure a set of intensities  $I_{RS}$  for such a reference sample ("RS"), we can sequentially eliminate  $\sigma_{++}$  and  $\sigma_{-}$  from equations (6-13, 14, 15, 16) (having set  $\sigma_{+-} = \sigma_{-+} = 0$ ) and solve for F in terms of the intensities  $I_{RS}$  and the other parameters FR, (1-2f), and (1-2r), which we have already determined from equations (6-18, 19, 20, 21). The result of these computations is the following expression for F:

For mular 
$$F = \frac{-B \pm \sqrt{B^2 - 4AC}}{2A}$$
 (6-22)

where

$$A = (1-2f) (I_{RS}^{\text{off on}} - I_{RS}^{\text{off off}}) + I_{RS}^{\text{on off}} - I_{RS}^{\text{on on}}$$

$$B = I_{RS}^{\text{off on}} [1 - FR (1-2f)]$$

$$- I_{RS}^{\text{off off}} [1 - FR (1-2f) (1-2r)]$$

$$+ I_{RS}^{\text{on off}} [1 - FR (1-2r)]$$

$$- I_{RS}^{\text{on on}} [1 - FR]$$

and

$$C = FR \cdot [I_{RS}^{\text{on on}} - I_{RS}^{\text{off on}} + (1-2r)(I_{RS}^{\text{off off}} - I_{RS}^{\text{on off}})].$$

Once F is so determined, R = FR/F and all instrumental parameters are known.

In order to illustrate the application of the instrumental corrections described here, consider the following example. The reflectivity of an Fe-Cr multilayer was measured on the polarized neutron reflectometer at NIST (Ankner et al., 1992) which was determined to have efficiencies F = 0.986, R = 0.924, f = 0.999, and r = 0.985 (using an Fe-Si multilayer sample as the calibration standard and following the procedure outlined above). The raw, uncorrected specular

Scale factors on slit soun

$$\beta(kA, kB, kC, kD) = \frac{1}{2} \frac{kAkD - kBkC}{kA + kO - kB' - kC}$$

$$= \frac{1}{2} \frac{k^2 AD - k^2 BC}{k(A+D-B-C)}$$

$$= \frac{R}{2} \frac{AD - BC}{A+O-B-C}$$

$$= R \beta(A, B, C, D)$$

$$FR(kA,kB) = \frac{kA}{2kB} - 1 = \frac{A}{2B} - 1 = FR(A,B)$$

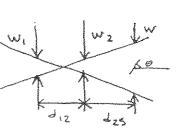
$$\chi(RB, RB, FR) = \frac{(RB-1)}{FR} = \frac{(B-1)}{FR} = \chi(B, B, FR)$$
  
 $\chi(RC, RB, FR) = \frac{(RB-1)}{FR} = \frac{(S-1)}{FR} = \frac{(S-1)}{FR} = \frac{(S-1)}{FR} = \frac{(S-1)}{FR}$ 

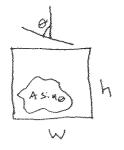
flip F, fliph depends on x,9, which are unchanged after scaling.

poir, poir depends on FR, Frration, which are unchanged after scaling.

For the actual correction, the system we are solving,

is independent of monitor.  $\begin{vmatrix} B \\ B \end{vmatrix} = \begin{vmatrix} B \\ B \end{vmatrix}$ 





$$I_{o} = r I A sin(\theta - \theta_{o})$$

$$I_{s} = I h w$$

$$\Gamma = \frac{I_0}{I_{A}\sin(\theta-\theta_0)} = \frac{I_0}{I_5} \left( \frac{I_5}{I_{A}\sin(\theta-\theta_0)} \right) = \frac{I_0}{I_5} \left( \frac{I_h w}{I_{A}\sin(\theta-\theta_0)} \right)$$

$$C = \frac{I_0}{I_s} \frac{hw}{Asin(\theta - \theta_0)}$$

$$\Theta < \Theta_C \Rightarrow r = 1 \Rightarrow A \sin(\Theta - \Theta_0) = \frac{I_0}{I_0} W$$

Fig prep: compute (I)W. Fit: determine A, -A, 00
Srow data, f, or data, s

from data.f or data.s

$$W_1 = S_{10} + S_{11}(20)$$
 $W_2 = S_{20} + S_{21}(20)$